

**Search Notes**

Application/Control No.

10/621,372

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under  
Reexamination

AKIYAMA ET AL.

Art Unit

1745

**SEARCHED**

Class	Subclass	Date	Examiner
429	12	5/17/2007	DWY
429	34	5/17/2007	DWY
429	35	5/17/2007	DWY

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
429	12	5/17/2007	DWY
429	34	5/17/2007	DWY
429	35	5/17/2007	DWY

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	5/17/2007	DWY
Inventorship Search	5/17/2007	DWY